

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20140130001 Hybrid Au/Cu wire bond flow for NFBGA Shiva and Freon Devices Change Notification / Sample Request

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 90 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN ww_admin_team@list.ti.com).

Sincerely,

PCN Team SC Business Services Phone: +1(214) 480-6037 Fax: +1(214) 480-6659

PCN# 20140130001 Attachment: 1

Products Affected:

According to our records, there are the affected device(s) that you have purchased within the past twenty-four (24) months. Technical details of this Product Change follow on the next page(s).

PCN Number:		2014	20140130001					PCN	Date:	04/08/2	014	
Title: Hybrid Au/Cu w			ı wire bor	re bond flow for NFBGA Shiva and Freon D				Devi	ces			
Customer Contact:			PCN Man	N Manager Phone: +1(214)480 6037				Dept:	Quality Services			
Proposed 1 st Ship Date:			:	07/08/2014 Estimated Sample Availabili				Date provided at sample request.				
Cha	nge Type:											
	Assembly					sign				ifer Bump		
	Assembly					ta Shee		Щ	_		Material	
	Assembly	Materials			-	t numb inge	er		Wa	ifer Bump	Process	
	Mechanica	I Specifica	ation		Test Site				Wafer Fab Site			
	Packing/S	hipping/La	beling	Test Process			Wa	Wafer Fab Materials				
									Wa	Wafer Fab Process		
					PCN	Deta	ils					
Des	cription of	Change:										
This is to Qualify a Hybrid Au/Cu wire bond flow for NFBGA Shiva and Freon Devices. See table below for reference: Material Set From To						!						
Wir	e diam (Mi	ils)	0.8mil Au	wire	0.8	Bmil Au,	/Cu wire					
	son for Ch											
 Continuity of supply. To align with world technology trends and use wiring with enhanced mechanical and electrical properties Maximize flexibility within our Assembly/Test production sites. Cu is easier to obtain and stock 												
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):												
None.												
Changes to product identification resulting from this PCN:												
None.												
Proc	luct Affect	ted:										
			0840K012	BZWT	WT300 OMAPL132BZWTA2R		42R	R	RZTHC6748			
AM1802BZWTD3			D840K012BZWT400			OMAPL132DZWTA						
			0K012BZWT456			OMAPL132DZWTA						
			0840K022				132EZWTA2R			TMS320C6742BZWT		
AM1806BZCEA3 D8		0840K022	2BZWT	300			١3	Т	TMS320C6746AZV			
		0840K022	BZWT			138AZWT3		Т	TMS320C6746BZCE3			
AM1806BZWT3 D85		0850K002	BZCE	300	OMAP	L138AZWT3	3SR	ΓТ	TMS320C6746BZCEA3		3	
AM1806BZWT4 D8			0850K002	BZCE	400	00 OMAPL13				TMS320C6746BZCED4		4
	1806BZWTI		0850K002	2BZCE456 OMAPL138			L138BZCE4	TMS320C6746BZWT3				
	AM1808BZCE3 D85			2BZWT			OMAPL138BZCEA3 TMS320C6			746BZWT3		
	1808BZCE4		D850K002BZWT400				L138BZCEA	BBZCEA3D TMS320C6		5746BZWT4		
AM1808BZCEA3			D850K002BZWT456 OM/			OMAP	L138BZCEA	BZCEA3E TMS320C6746BZWT/			ر.3	

AM1808BZCED4	D850K012BZCE300	OMAPL138BZCEA3R	TMS320C6746BZWTD4
AM1808BZWT3	D850K012BZCE400	OMAPL138BZCED4	TMS320C6748AZCE3
AM1808BZWT4	D850K012BZCE456	OMAPL138BZCED4E	TMS320C6748AZWT3
AM1808BZWTA3	D850K012BZWT300	OMAPL138BZCEML	TMS320C6748BZCE3
AM1808BZWTD4	D850K012BZWT400	OMAPL138BZWT3	TMS320C6748BZCE4
AM1808BZWTT3	D850K012BZWT456	OMAPL138BZWT4	TMS320C6748BZCEA3
AM1810BZWTA3	D850K018BZWT400	OMAPL138BZWTA3	TMS320C6748BZCEA3E
AM3505AZCN	D850K022BZCE300	OMAPL138BZWTA3CS	TMS320C6748BZCED4
AM3505AZCNA	D850K022BZCE400	OMAPL138BZWTA3E	TMS320C6748BZCED4E
AM3505AZCNAC	D850K022BZCE456	OMAPL138BZWTA3R	TMS320C6748BZWT3
AM3505AZCNC	D850K022BZWT300	OMAPL138BZWTA4	TMS320C6748BZWT3CS
AM3517AZCN	D850K022BZWT400	OMAPL138BZWTD4	TMS320C6748BZWT4
AM3517AZCNA	D850K022BZWT456	OMAPL138BZWTD4E	TMS320C6748BZWTA3
AM3517AZCNAC	DCHGC6748	OMAPL138BZWTRB	TMS320C6748BZWTA3E
D840K002BZCE300	M10MAPL138DZCE	OMAPL138CZWTA3RW	TMS320C6748BZWTD4
D840K002BZCE400	M10MAPL138DZCER	OMAPL138CZWTD4RW	TMS320C6748BZWTD4E
D840K002BZCE456	M10MAPL138EZCER	OMAPL138DZCEA3	TNETV138BINZWT4
D840K002BZWT300	M10MAPL138ZCE	OMAPL138DZCEA3R	XAM1808BZCE4
D840K002BZWT400	M10MAPL138ZCER	OMAPL138DZWTA3	XOMAPL138BZCE
D840K002BZWT456	OMAPL132BZWT2	OMAPL138DZWTA3R	XOMAPL138EZCEA3R
D840K012BZCE400	OMAPL132BZWTA2	OMAPL138EZCEA3R	XOMAPL138EZWTA3
D840K012BZCE456	OMAPL132BZWTA2E	OMAPL138EZWTA3R	XOMAPL138EZWTA3R

Qualification DataThis qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qual Vehicle 1: AM3517ZCN (MSL 3-260C)

Package Construction Details					
Assembly Site:	TI-PHI	Mold Compound:	4205283		
# Pins-Designator, Family:	491-ZCN, BGA	Mount Compound:	4205412		
Solder Ball composition	SnAgCu	Bond Wire:	0.80Mil Au/Cu		

Qualification: Plan Test Results

Reliability Test	Conditions	Sample Size/Fail			
Reliability Test	Conditions	Lot#1	Lot#2	Lot#3	
** Biased HAST	130C/85%RH (264 HRS)	77/0	77/0	77/0	
**Unbiased HAST	130C/85%RH (192 HRS)	77/0	77/0	77/0	
**T/C	-55C/+125C (1000 Cyc)	77/0	77/0	77/0	
**High Temp Storage Bake	150C (1000 Hrs)	20/0	20/0	20/0	
ESD CDM	+/- 250V	3/0	3/0	3/0	
Manufacturability	(per mfg. Site specification)	Pass	ı	-	
Notes **- Preconditioning sequence: Level 3-260C.					

Qual Vehicle 2: AM1808BZCE4 (MSL 3-260C)							
Package Construction Details							
Assembly Site:	TI-PHI	PHI Mold Compound:		4208515			
# Pins-Designator, Family:	361-ZCE, BGA	Mount Compound:	42054	12			
Solder Ball composition	SnAgCu	Bond Wire: 0.80Mil Au/		l Au/Cu			
Qualification:		Test Results					
Reliability Test	Coi	Conditions		Sample Size/Fail			
ESD CDM	+/- 250V; +/- 5	+/- 250V; +/- 500v; +/- 750V			3/0		
Manufacturability	(per mfg. Site s	pecification)		Pass			
Qual	Vehicle 3: OMAPL	138BZWTQ3 (MSL 3	3-260C)				
	Package Con	struction Details					
Assembly Site:	TI-PHI	Mold Compound:	42085	4208515			
# Pins-Designator, Family:	361-ZWT, BGA	Mount Compound:	42054	12			
Solder Ball composition	SnAgCu	Bond Wire:	Bond Wire: 0.80Mil Au/Cu				
Qualification:	☐ Test Results		•				
Reliability Test	Сог	Conditions		Sample Size/Fail			
ESD CDM	+/- 250V; +/- 5	+/- 250V; +/- 500v; +/- 750V		3/0			
Manufacturability	(per mfg. Site s	(per mfg. Site specification) Pass					
Qual Ve	Qual Vehicle 4: TMS320C6748BZWTA3E (MSL 3-260C)						
	Package Con	struction Details					
Assembly Site:	ΓΙ-PHI Mold Compound:		4208515				
# Pins-Designator, Family:	361-ZWT, BGA	•		4205412			
Solder Ball composition	SnAgCu			0.80Mil Au/Cu			
Qualification:							
Reliability Test	Cor	Conditions		Sample Size/Fail			
Reliability Test	Col			Lot#2	Lot#3		
** Biased Temp and Humidit	y 85C/85%RH (1	85C/85%RH (1000 Hrs)		26/0	26/0		
**Unbiased HAST		110C/85%RH (264 Hrs)		77/0 77/0	77/0		
**T/C		-55C/+125C (1000 Cyc)			77/0		
**High Temp Storage Bake		150C (1000 Hrs)			77/0		
Notes **- Preconditioning sequence: Level 3-260C.							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com